Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/160,267	TOYAMA ET AL.	
Examiner	Art Unit	
Douglas Q. Tran	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED						
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	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
HPL (IEEE)	12/12/05	A		